

5-25-04

**ELECTRONIC INFORMATION DISCLOSURE STATEMENT**

Electronic Version v18

Stylesheet Version v18.0

<b>Title of Invention</b>	<b>INCREASE PRODUCTIVITY AT WAFER TEST USING PROBE RETEST DATA ANALYSIS</b>
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Application Number : 10/709,721

Confirmation Number:

First Named Applicant: Akiko Balchiunas

Attorney Docket Number: BUR920040137US1

Art Unit: 2829

Examiner: TANG

Search string: ( 6240329 or 6350959 or 6507800 or 6618682 or 20030120445 or 20030139839  
) .pn**US Patent Documents****Note: Applicant is not required to submit a paper copy of cited US Patent Documents**

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
MA	1	6240329	2001-05-29	Sun			
	2	6350959	2002-02-26	Beffa			
	3	6507800	2003-01-14	Sheu			
MA	4	6618682	2003-08-09	Bulaga et al.			

**US Published Applications****Note: Applicant is not required to submit a paper copy of cited US Published Applications**

init	Cite.No.	Pub. No.	Date	Applicant	Kind	Class	Subclass
MA	1	20030120445	2003-06-26	Barbour et al.			
MA	2	20030139839	2003-07-24	Beffa			

**Signature**

7/25/06

Examiner Name	Date

